

# Attivita' italiane su FD-HD

Nov 12, 2021

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# Remainder of the strategy

DUNE is pursuing a «two vendor scheme» for the procurement of the SiPMs for FD1-HD (288,000+spares) because of:

- Risk mitigation (retirement/disappearance of a vendor, as it happened with SensL a few years ago)
- Cost reduction (multiple bids)

We call it a «two vendor» scheme because in the preparatory phase we identified two vendors able to produce such an amount of cryogenic SiPMs and certify them at 87 K

## **Hamamatsu Photonics (HPK)**

A Japanese company with satellite distribution companies in US and EU

## **Fondazione Bruno Kessler (FBK)**

An Italian company serving particle and astroparticle experiments (CTA, CMS, DarkSide, LHCb, etc.)

# Timeline

Design of customized SiPMs  
(Q2 2019- Q1 20)

Test of 25-sensor batches  
(Q3-4 20)

Test of 250-sensor  
batches (Q2 21)

Downselection (Q2-3 21)

Production of 4k+4k SiPMs for  
ProtoDUNE Run II (Q4 21)

Orders for FD1 (Q2 22)

Start of production (Q4 22)

Design of customized SiPMs  
(Q2 2019- Q1 20)

Test of 25-sensor batches  
(Q3-4 20)

Test of 250-sensor  
batches (Q2 21)

Downselection (Q2-3 21)

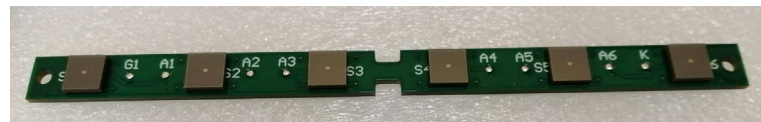
Orders for FD1  
(Q4 21 – Q2 22)

Production of 4k+4k  
SiPMs for ProtoDUNE  
Run II (Q4 21)

Start of production (Q4 22)

# Specifications

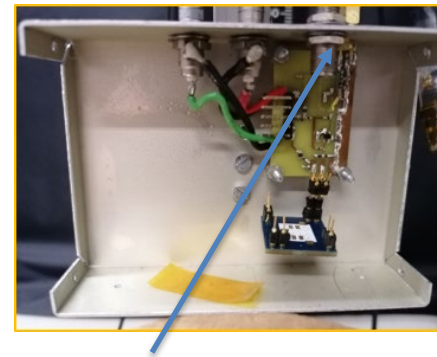
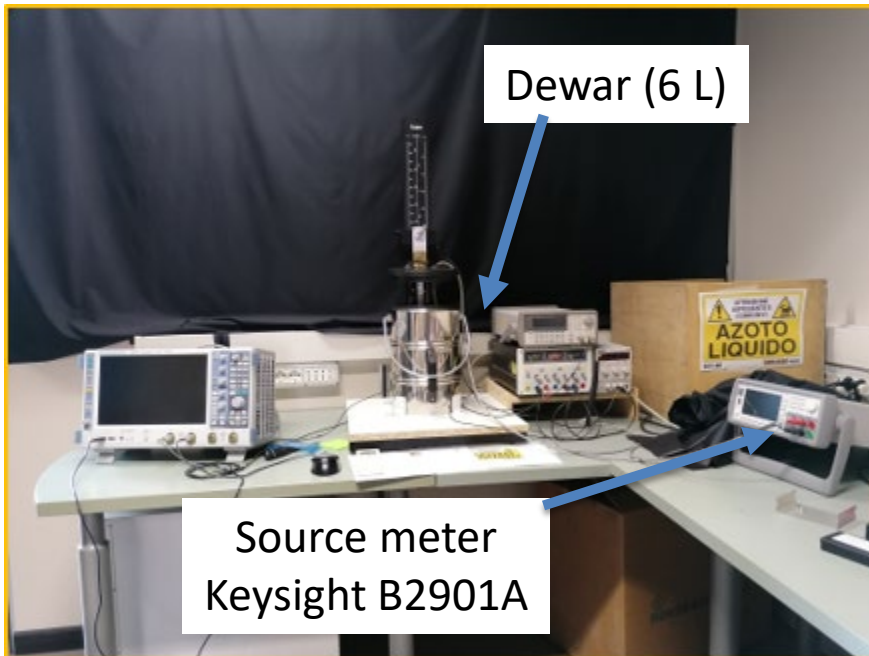
- Test 6 types of SiPMs 6x6 mm<sup>2</sup> developed **specifically for DUNE**.  
«splits»: 4 from Hamamatsu (HPK) and 2 from FBK
- 25 SiPMs per type fully characterized at single SiPM level
- 250 SiPMs per type in the DUNE SiPM board, tested at single SiPM level and in ganging



Parameter	value	note
Breakdown Voltage	<50 V	All splits
PDE at 430 nm	>35 % at nominal overvoltage	Achieved 45% for downselected splits
x-talk and afterpulse	<35% at nominal OV	Updated after the reanalysis of throughput
Rise time	<100 ns	not critical
Recovery time	a few $\mu$ s	Not critical
Thermal cycles	>20	<b>Achieved by all splits!!</b>

# Facilities for full test

- Bologna and Milano Bicocca setup 2 pilot stations capable to fully characterize SiPM at cryogenic temperature ( $V_{br}$ ,  $R_q$ ,  $D_{cr}$ )



Amplifier  
(each lab used a  
custom amp..good  
xcheck)

- After short time also the other labs built their system complying a set of requirements: Ferrara, NIU, Madrid, Valencia, Prague,

# Test protocol

- Bologna and Milano Bicocca setup testing protocol
- Ferrara, NIU, Madrid, Valencia, Mi, Mib, Bologna, Prague labs were involved in the tests
- Same test procedures and compatible instrumentation to guarantee uniformity of results
- Combine all measurements

## Planning for the SiPM tests in the DUNE pre-production phase

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Version 5, 21 April 2020

### 1 The pre-production phase

In 2019, the DUNE Single Phase Photon Detection System (SP-PDS) Consortium set up an agreement with two vendors in view of the production of the SiPMs for first DUNE Module (288000 sensors). The vendors – Fondazione Bruno Kessler (FBK) and Hamamatsu Photonics (HPK) – agreed to optimize their SiPM technologies for the needs of DUNE and certify the sensors for operation at 87 and 77 K. In 2018-2019, we down-selected two technologies that will be at focus in the pre-production phase (2020-2022):

- The Hole Wire Bond (HWB) technology of HPK implemented in the S13360 chip with Silicon package.
- The NUV-HD-Cryo technology of FBK implemented in SMD epoxy resin package.

All sensors will be produced in the DUNE form factor:  $6 \times 6 \text{ mm}^2$ . The aim of the pre-production is to down-select one sensor per vendor and produce 3000 SiPMs for FBK and 3000 SiPMs for HPK to be installed in ProtoDUNE-SP. The sensors will be installed in 30 X-ARAPUCA modules (3 APA) and tested in the Run II. The pre-production activities will culminate in the complete validation of the DUNE PDS during Run II in order to start the mass production phase.

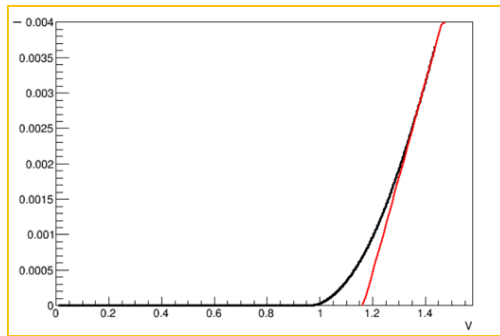
### 2 The FBK and HPK splits

The NUV-HD-Cryo technology developed by FBK and implemented, for instance, in the Dark Side experiment, fulfills all basic specifications for DUNE. It has never been used for  $6 \times 6 \text{ mm}^2$  sensors and with the SMD package. As a consequence, the main DUNE production split that will be made by FBK

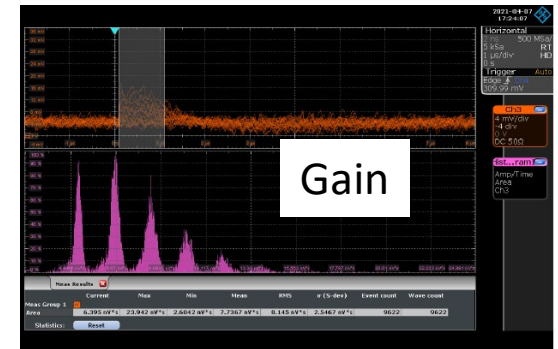
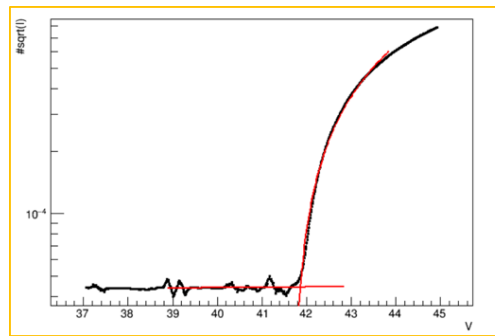
# What we measure

- First of all the IV curves

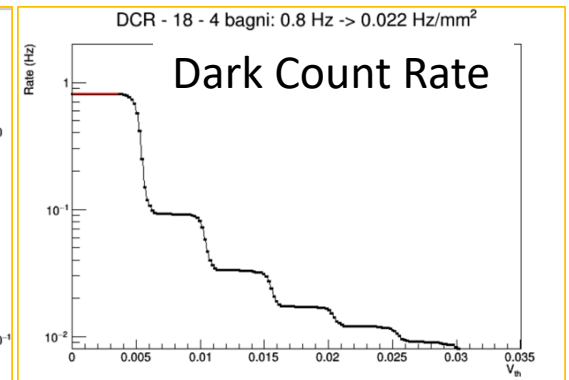
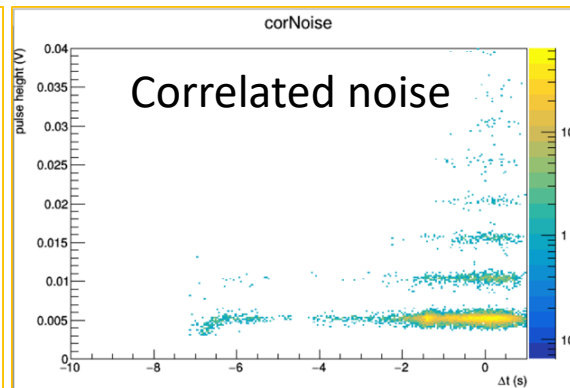
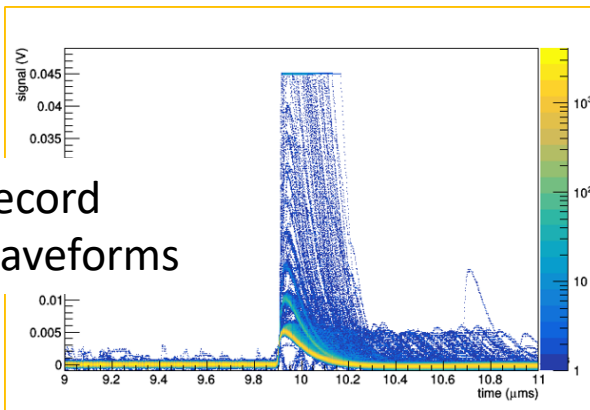
- direct bias:  $R_q$ ,



inverse bias  $\rightarrow V_{br}$



Record waveforms



# Data analysis

- All measurements on Hamamatsu sent to Madrid
- All measurements on FBK to Milano Bicocca
- A lot of work to check consistency of results from different labs and average all data

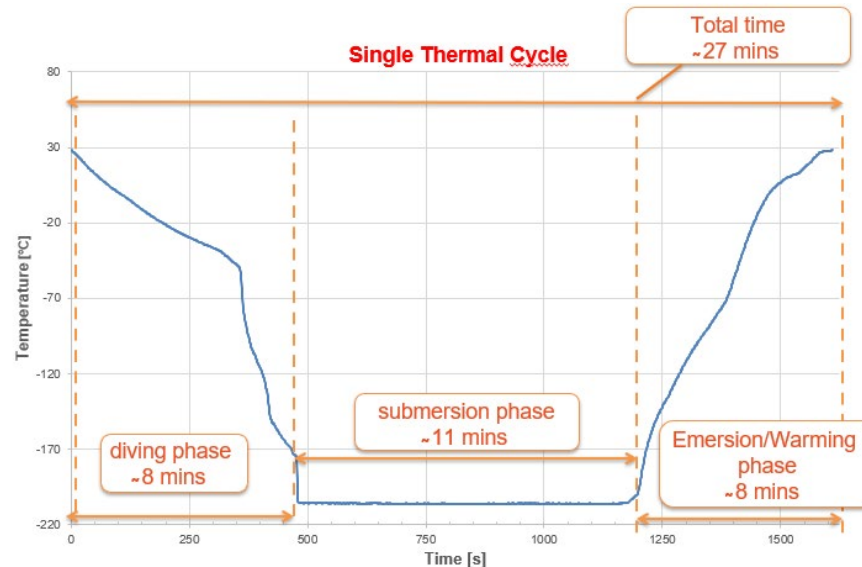
## Example for Hamamatsu

LABS INVOLVED		Model	PDE (%)	Gain		DCR+B (mHz/mm <sup>2</sup> )		DCR-B (mHz/mm <sup>2</sup> )		Xtalk (%)		Afterpulses(%)	
				Mean	Std Dev	Mean	Std Dev	Mean	Std Dev	Mean	Std Dev	Mean	Std Dev
Valencia Madrid Bicocca	Prague Ferrara Bologna	50_LQR	40	2,38E+06	6,60E+03	54,08	0,96	12,79	0,67	9,96	0,47	2,15	0,15
			45	3,10E+06	8,97E+03	60,29	1,06	13,70	0,70	11,23	0,39	2,62	0,17
			50	3,84E+06	8,57E+03	71,92	1,01	16,62	0,85	13,38	0,37	5,13	0,21
Valencia Madrid Bicocca	50_HQR	40	2,25E+06	6,65E+03	38,74	0,98	7,36	0,83	7,15	0,34	2,06	0,16	
		45	2,99E+06	6,79E+03	81,57	1,68	8,73	0,68	8,71	0,34	3,50	0,19	
		50	3,78E+06	8,04E+03	53,25	0,92	9,65	0,46	10,92	0,36	3,95	0,21	
Ferrara Bologna	Valencia Madrid	75_LQR	40	3,49E+06	6,72E+03	42,14	0,65	6,10	0,32	9,47	0,32	1,41	0,15
			45	4,33E+06	6,26E+03	50,70	0,75	6,58	0,34	10,18	0,35	1,83	0,16
			50	5,16E+06	7,61E+03	50,88	0,68	9,07	0,41	11,84	0,34	2,96	0,18
Bicocca Prague NIU	75_HQR	40	3,94E+06	2,02E+05	26,40	2,12	4,60	0,24	6,16	0,05	1,63	0,44	
		45	5,43E+06	2,34E+05	31,32	0,65	5,57	0,17	7,03	0,30	2,35	0,66	
		50	5,81E+06	2,73E+05	32,53	4,68	6,46	0,73	9,85	0,14	2,78	0,23	



# Thermal tests

- For test for downselection at least 20 cycle were required for qualification.



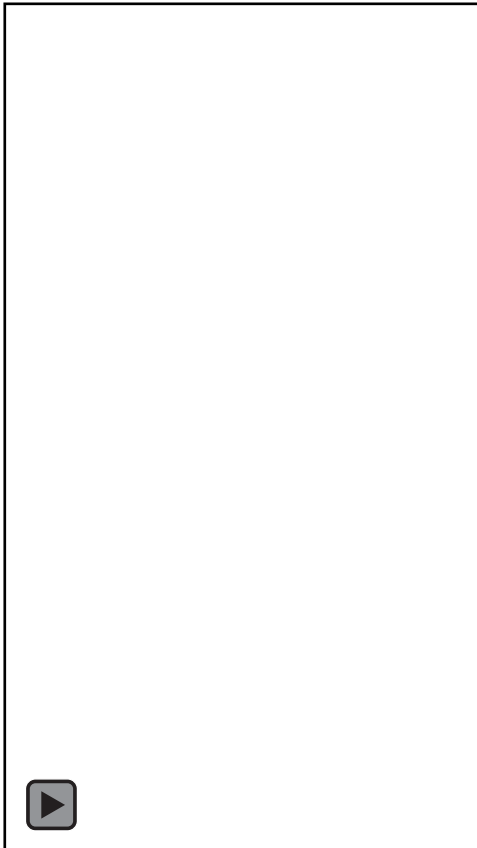
- Time consuming, risk of damage a working device. We are studying the aging factors.
- For mass production only 2 or 3 thermal cycles will be done. (time for test reduced by almost a factor 2!)



# Extreme thermal tests

- We tested performances before and after extreme thermal cycles..

From room temperature  
to 77K



From 77K to  
Room temperature



# High level specs

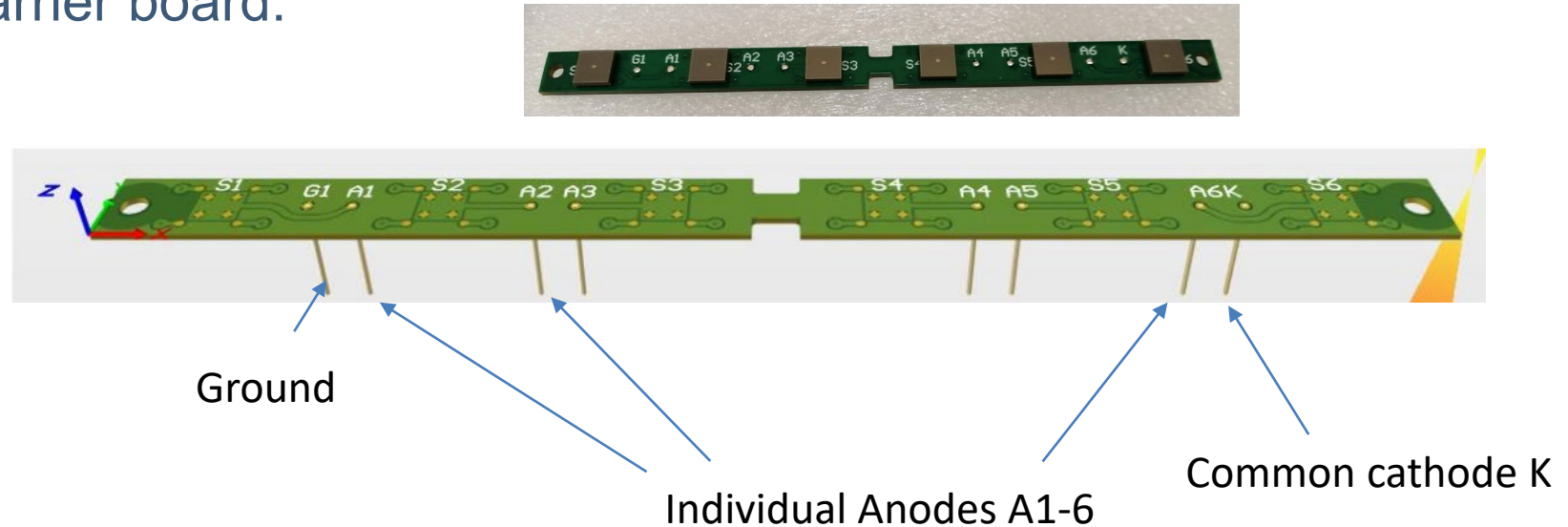
- Sensitivity to single p.e. at the level of one electronic channel and dynamic range for 48 SiPM > 2000 p.e.
- Dark count rate contribution negligible compared with background of  $^{39}\text{Ar}$

## NEW! Low level specs generated by the high-level specs

Parameter	value	note
Uniformity of $V_{\text{bk}}$	0.1 V per channel	Achieved by both vendors Agreed on 200pcs lots for mass production
Gain at nominal OV	$10^6$	Cell pitch of the downselected SiPMs: 75 $\mu\text{m}$ (HPK) and 50 $\mu\text{m}$ (FBK)
<b>S/N ratio for 1 p.e. with the PDS cryogenic amplifier</b>	<b>&gt; 4 sigma</b>	<b>OK for downselected SiPMs</b>
Dark Count rate	<60 mHz/mm <sup>2</sup> (<200 mHz/mm <sup>2</sup> )	OK for all splits. Can be relaxed because of the 1.5 p.e. trigger
Terminal capacitance	<0.060 nF/mm <sup>2</sup>	Updated after the release of the PDS cryogenic amplifier

# Test of SiPM mounted on PCB

- 250 SiPM per each type were produced and mounted on the carrier board:

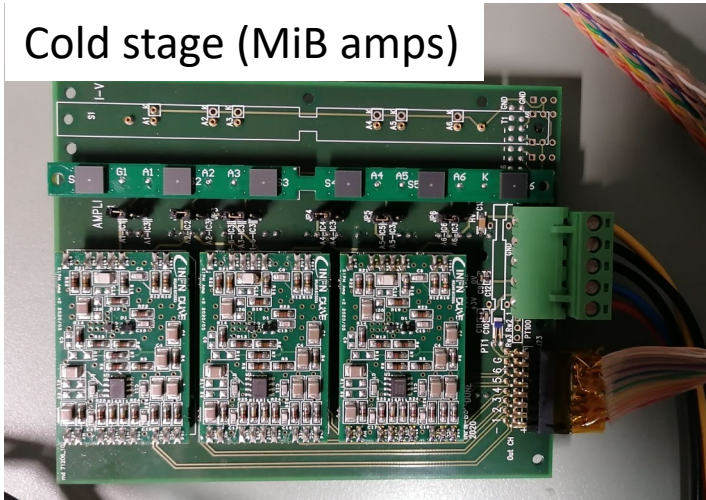


In the original design all the anodes were put together..no way to test each sigle SiPM and uniformity of breakdown voltage

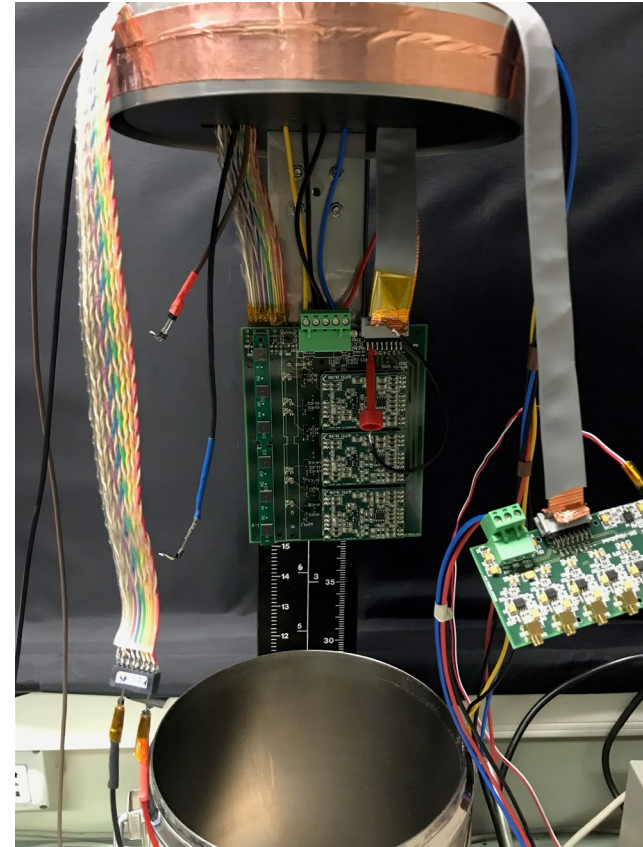
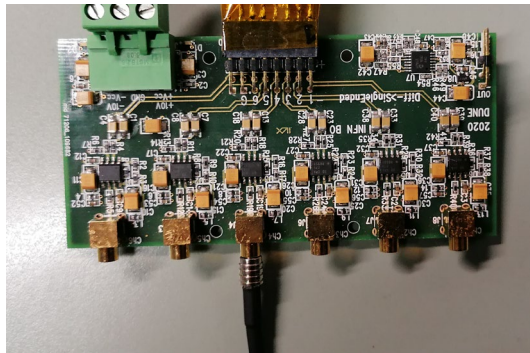
# Test board with cryogenic amp

- We developed and distributed to each lab a test board for arrays

Cold stage (MiB amps)



Warm stage (diff to single)



# Cold electronics

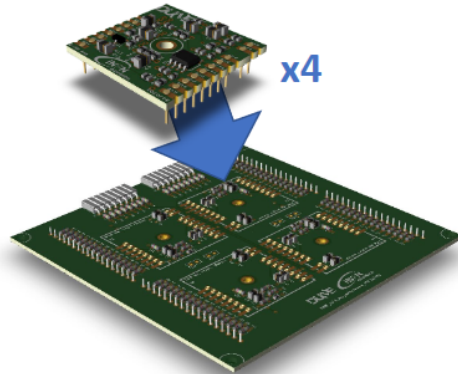
## Design

Cold amplifier design based on discrete commercial components:

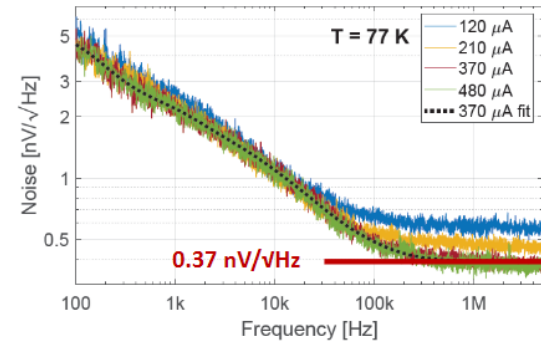
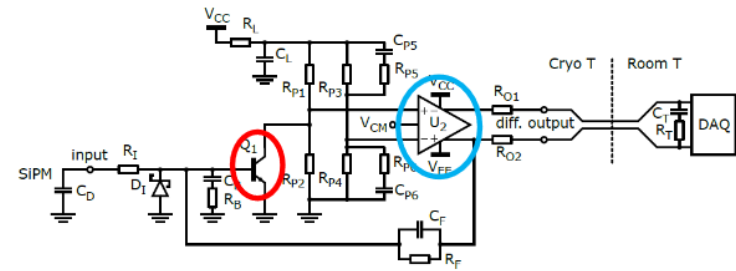
- **BFP640 SiGe bipolar transistor** at the input gives low voltage noise (0.4 nV/√Hz)
- **THS4531 differential opamp** gives high loop gain, differential outputs on 100 ohm line
- Single 3.3 V supply, ≈2 mW power consumption per channel
- 70 ns signal rise time, 2000 p.e. dynamic range\*
- <https://doi.org/10.1088/1748-0221/15/01/P01008>

\*depends on SiPM gain and overvoltage

Single channel daughter cards mounted on 4-channel motherboards

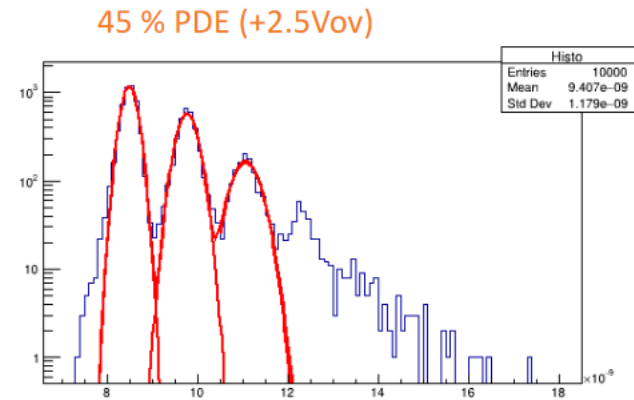
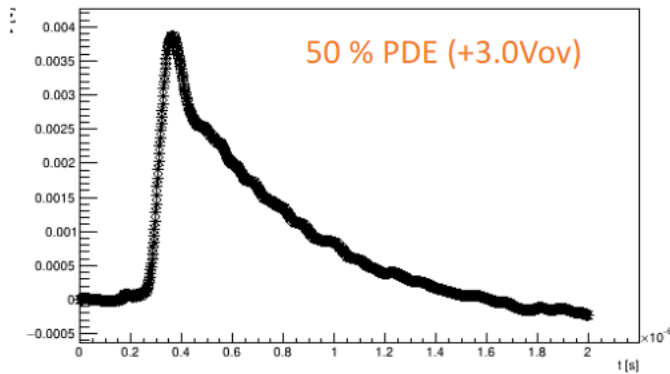


## Gotti - MiB



# Ganging 48 SiPM Hamamatsu

Ganging results: HPK 75HR



Average single p.e. signal

- After second stage with gain x10
- Cold amp diff output peaks at  $\approx 380\text{uV}$  @  $3\text{Vov}$   $\rightarrow \approx 130\text{uV/Vov}$
- Saturation at  $\approx 750\text{ mV}$   $\rightarrow \approx 5900\text{ p.e.} \times \text{Vov}$   
 $\rightarrow$  Dynamic range  $> 2000\text{p.e.}$  if  $\text{Vov} < 3.0\text{ V}$

PDE	Vov	DR(p.e.)	SN_0	SN_1	SN_2
40%	2.0	$\approx 2900$	6.30	5.21	3.13
45%	2.5	$\approx 2350$	7.49	5.96	4.17
50%	3.0	$\approx 2000$	8.92	6.66	5.22

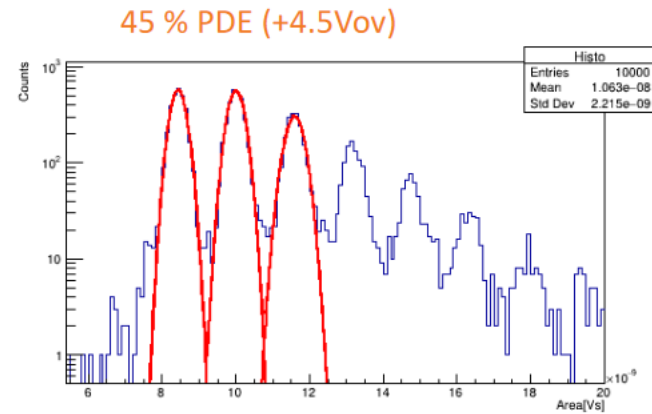
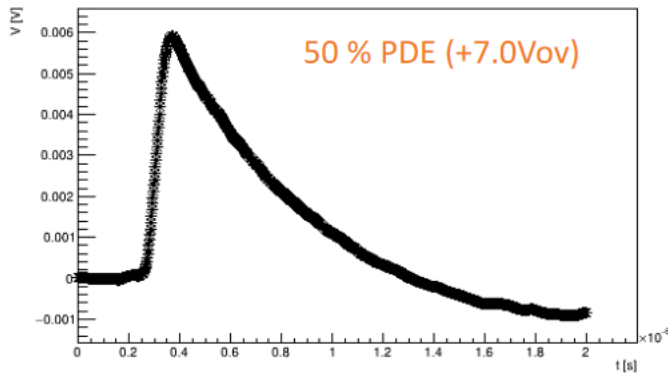
$$\text{SN}_x = [1 \text{ p.e. peak}] / [x \text{ p.e. sigma}]$$

Results obtained in Milano-Bicocca

Similar numbers were obtained in Madrid & Milano Statale

# Ganging 48 SiPM FBK

Ganging results: FBK 3T (50um)



## Average single p.e. signal

- After second stage with gain x10
- Cold amp diff output peaks at  $\approx 600\mu\text{V}$  @  $7\text{Vov} \rightarrow \approx 85\mu\text{V/Vov}$
- Saturation at  $\approx 750\text{ mV} \rightarrow \approx 8800\text{ p.e.} \times \text{Vov}$   
 $\rightarrow$  Dynamic range  $> 2000\text{p.e.}$  if  $\text{Vov} < 4.5\text{ V}$

PDE	Vov	DR(p.e.)	SN_0	SN_1	SN_2
40%	3.5	$\approx 2500$	5.64	5.69	5.14
45%	4.5	$\approx 2000$	7.56	7.16	6.30
50%	7.0	$\approx 1250$	11.32	10.34	9.52

$$\text{SN}_x = [1 \text{ p.e. peak}] / [x \text{ p.e. sigma}]$$

Results obtained in Milano-Bicocca

Similar numbers were obtained in Madrid & Milano Statale

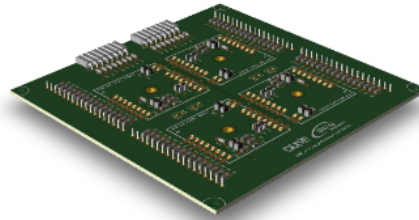


# Status of cold electronics

## Status & numbers

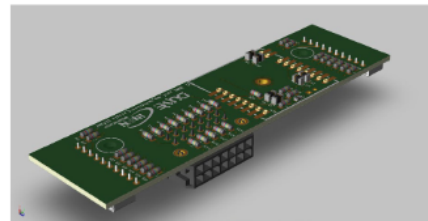
### 4-ch Motherboard (v02)

- 24x available
  - 10 for cold box test at CERN
  - 4 at CSU
  - 2 MiB
  - 8 to other labs / spares



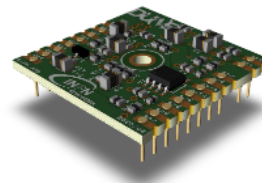
### 1-ch Motherboard for single supercell tests

- 40x available
  - ≈30 for SC tests at CIEMAT
  - ≈ 10 to other labs

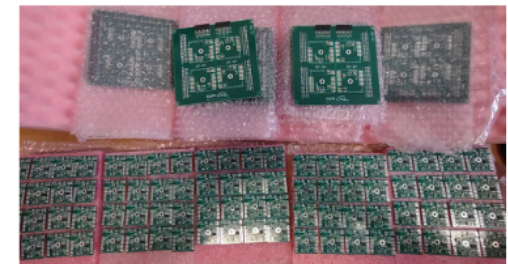


### Cold Amplifier (v02)

- 80x available
  - 40 for cold box test at CERN
  - 30 for SC tests at CIEMAT, to be shared after the tests
  - 10 to other labs / spares



- Quantities required for the Cold Box Test at CERN: 10x MB, 40x amplifiers
  - Already available
- Quantities required for ProtoDUNE2: 40x MB, 160x amplifiers
  - ≈30x 4chMB and ≈100x amplifiers to be ordered in autumn





# Next steps

## Electrical Supercell test for FDR

- Electrical tests performed for HPK at Milano-Statale
- Ongoing: replacement of HPK 70 $\mu$ m LQR with FBK Triple Trench to validate the downselected FBK sensors (October)
- [supercell test with LAr: see **C.Cattadori's talk**]

## SiPM for ProtoDUNE Run II:

- We already have 250+250 SiPMs that will be used for the two modules of November's Cold Box Test – **critical: complete the supercell test in October/November**
- FBK: 4000 sensors will be delivered by the end of November
- HPK: 4000 sensors will be delivered by December (uncertainty of a few weeks due to an issue experienced by HPK with the quenching resistors – **may be critical for January's cold box test where we need 2000 SiPMs (by any vendor). Start test in December with FBK SiPMs**)
- Mass tests: see **Marco Guarise's talk**

# Conclusions

- Downselection: the preproduction phase is over. It was very successful and well within schedule.
- We downselected:

**S13360 75 $\mu$ m High Quenching Resistance from Hamamatsu  
NUV-HD-CRYO 50 $\mu$ m with Triple Trenches from FBK**

- 5/6 splits fully on specs. We chose the ones with better S/N (higher cell pitch at fixed PDE)
- We are preparing the Final Design Review (lead: Philippe Farthouat) in Spring
- On the critical path: cold box test (2 modules, 384 SiPMs) and in January (10 modules, 1920 SiPMs)